

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/823,759	CHEN ET AL.
	Examiner	Art Unit
	Hana A. Sanei	2879

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>